

Enhanced conductivity in (110)-textured ScSZ films tuned by amorphous alumina interlayer

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Supporting information

Table S1 Texture coefficient values calculated using Harrish equation from θ - 2θ XRD patterns for 10ScSZ and AO/10ScSZ films

	as-deposited	600 °C	800 °C	1000 °C
10ScSZ ($f_{(111)}$)	2.87	2.89	2.68	2.01
10ScSZ ($f_{(110)}$)	0.20	0.23	0.54	1.44
AO/10ScSZ ($f_{(110)}$)	1.52	1.56	1.84	1.91

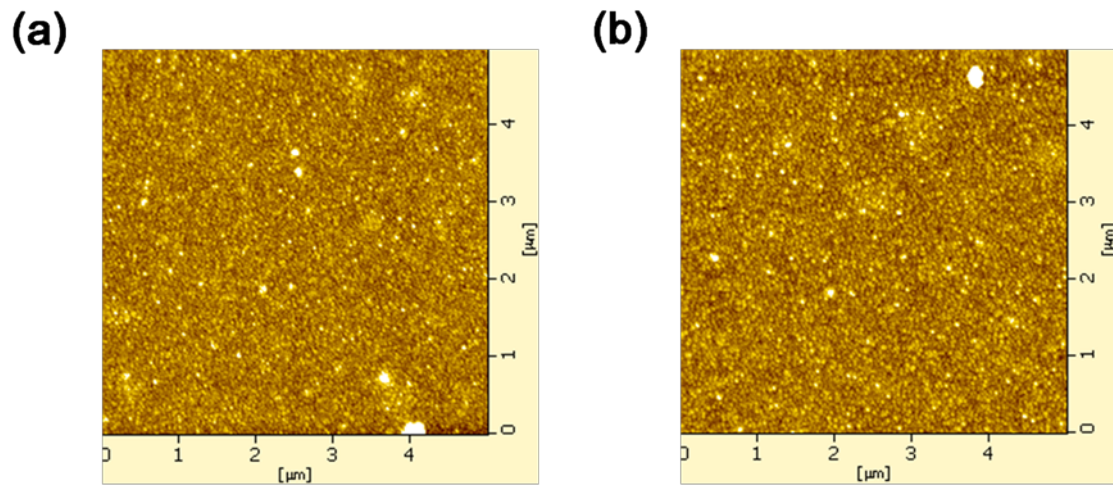


Fig. S1 Typical AFM images of the (a) AO/10ScSZ and (b) 10ScSZ thin films.

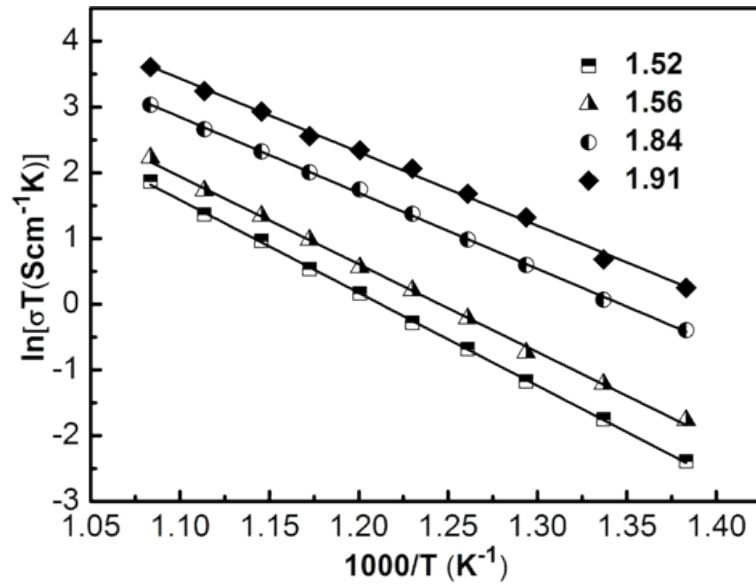


Fig. S2 Arrhenius plots of AO/10ScSZ thin films with different $f_{(110)}$ values.